



PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Jon Opsal et al.

Application No.: 10/658,176

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For: CRITICAL DIMENSION ANALYSIS  
WITH SIMULTANEOUS MULTIPLE  
ANGLE OF INCIDENCE  
MEASUREMENTS

Confirmation No.: 3341

Group Art Unit: 2877

Examiner: Richard A. Rosenberger

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Box 1450 Alexandria, VA 22313-1450 on June 11, 2004.  
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